

Description

The FDS4435BZ uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.



SOP-8 (SOIC-8)

General Features

 $V_{DS} = -30 V I_{D} = -11 A$

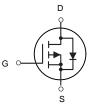
 $R_{DS(ON)}$ < 16m Ω @ V_{GS} =10V

Application

Battery protection

Load switch

Uninterruptible power supply



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
FDS4435BZ	SOP-8(SOIC-8)	4435 XXX YYY	3000

Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	- 30	V
VGS	Gate-Source Voltage	±20	V
ID@T _A =25°C	Drain Current ³ , V _{GS} @ 10V	-11	А
IDM	Pulsed Drain Current ¹	-40	А
PD@Ta=25°C	Total Power Dissipation	3.7	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Rthj-a	Maximum Thermal Resistance, Junction-ambient ³	33.8	°C/W



Electrical Characteristics (T_J = 25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units		
Off Charac	Off Characteristic							
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = -250μA -30		-	-	V		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -30V, V _{GS} =0V,	-	-	-1	μA		
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA		
On Charac	n Characteristics							
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D = -250μA	-1.0	-1.6	-2.5	V		
R _{DS(on)}	Static Drain-Source on-Resistance	V _{GS} = -10V, I _D = -10A	-	13	16	mΩ		
1 103(011)	Note3	V_{GS} = -4.5V, I_{D} = -5A	- 18 27		27			
Dynamic (Characteristics							
C _{iss}	Input Capacitance	\\	-	1330	-	pF		
C_{oss}	Output Capacitance	V _{DS} = -15V, V _{GS} =0V, f=1.0MHz	-	183	ı	pF		
C_{rss}	Reverse Transfer Capacitance	1-1.0WII 12	-	156	-	pF		
Q_g	Total Gate Charge	\/ 45\/ L 5A	-	22	-	nC		
Q_{gs}	Gate-Source Charge	V_{DS} = -15V, I_D = -5A, V_{GS} = -10V	-	1.0	ı	nC		
Q_{gd}	Gate-Drain("Miller") Charge	VGS10V	-	1.8	ı	nC		
Switching	Characteristics							
t _{d(on)}	Turn-on Delay Time	V _{DD} = -15V, I _D = -10A,	-	9	-	ns		
t _r	Turn-on Rise Time		_	13	-	ns		
t _{d(off)}	Turn-off Delay Time	V_{GS} =-10V, R_{GEN} =2.5 Ω	_	48	-	ns		
t _f	Turn-off Fall Time		-	20	-	ns		
Drain-Sou	rce Diode Characteristics and Maximu	m Ratings						
Is	Maximum Continuous Drain to Source Diode Forward Current		-	-	-11	Α		
I _{SM}	Maximum Pulsed Drain to Source Diod	e Forward Current	-	-	-40	Α		
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S = -15A	-	-0.8	-1.2	V		
trr	Reverse Recovery Time	TJ=25℃,	-	64	ı	ns		
Qrr	, ,	V_{DD} = -24V, I_F =-2.8A, dl/dt=-100A/ μ s	-	25	-	nC		

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition: T_J =25 $^{\circ}$ C, V_{GS} =10V, R_G =25 Ω , L=0.5mH, I_{AS} =-12.7A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%



Typical Characteristics

Figure1: Output Characteristics

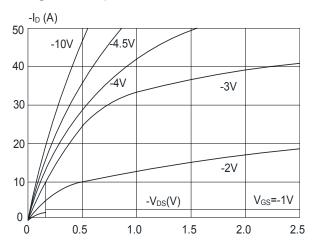


Figure 3:On-resistance vs. Drain Current

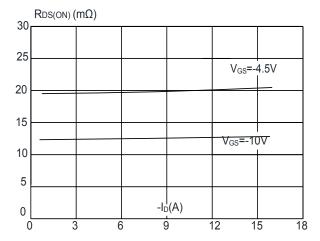


Figure 5: Gate Charge Characteristics

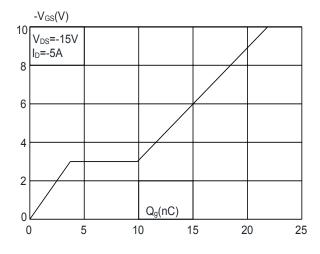


Figure 2: Typical Transfer Characteristics

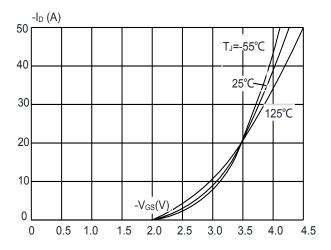


Figure 4: Body Diode Characteristics

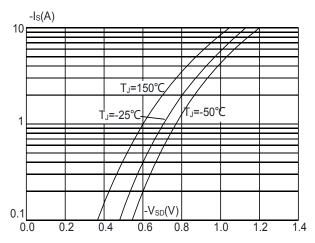


Figure 6: Capacitance Characteristics

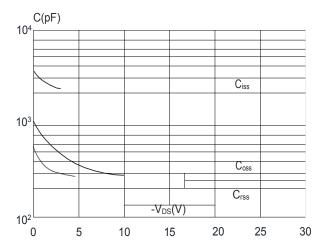




Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

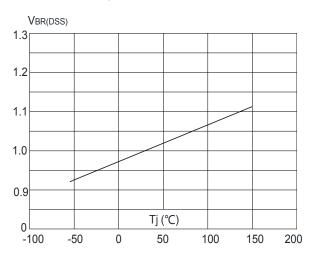


Figure 9: Maximum Safe Operating Area

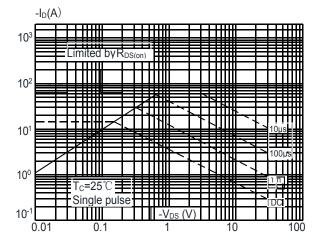


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

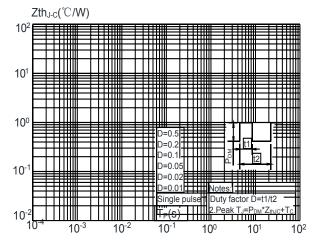


Figure 8: Normalized on Resistance vs. Junction Temperature

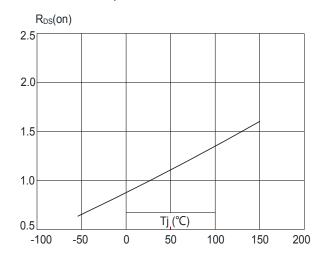
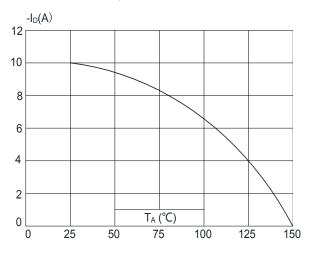


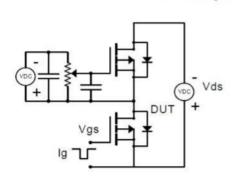
Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

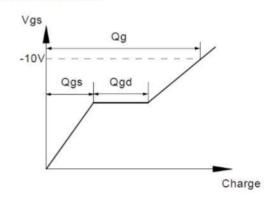




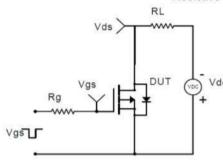
Test Circuit

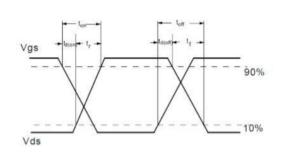
Gate Charge Test Circuit & Waveform



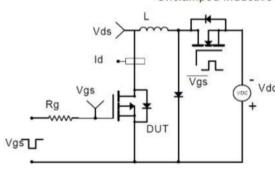


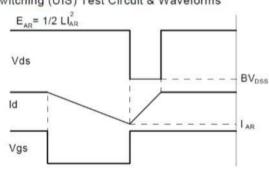
Resistive Switching Test Circuit & Waveforms



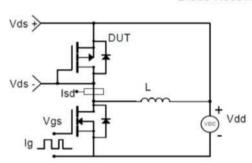


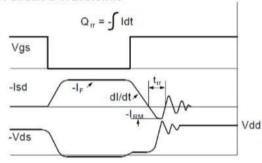
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





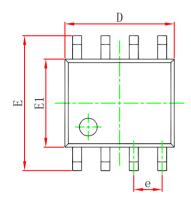
Diode Recovery Test Circuit & Waveforms

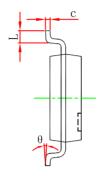


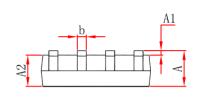




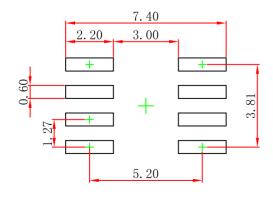
SOP-8(SOIC-8) Package Outline Dimensions







Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1. 350	1.750	0.053	0.069	
A1	0.100	0. 250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
c	0.170	0. 250	0.007	0.010	
D	4.800	5.000	0.189	0. 197	
e	1.270 (BSC)		0.050 (BSC)		
E	5.800	6. 200	0. 228	0. 244	
E1	3.800	4.000	0.150	0. 157	
L	0.400	1. 270	0.016	0.050	
θ	0°	8°	0°	8°	



- Note: 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.



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